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| Notice of References Cited | Application/Control No. 10/737,229 | Applicant(s)/Patent Under Reexamination AYER ET AL. | |
| | Examiner Navin Natnithithadha | Art Unit 3735 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|------------------------|----------------|
| * | A | US-5,279,607 A | 01-1994 | Schentag et al. | 604/890.1 |
| * | B | US-5,697,384 A | 12-1997 | Miyawaki et al. | 128/899 |
| * | C | US-2002/0132226 A1 | 09-2002 | Nair et al. | 435/4 |
| * | D | US-2003/0191430 A1 | 10-2003 | D'Andrea et al. | 604/66 |
| * | E | US-6,632,175 B1 | 10-2003 | Marshall, Daniel R. | 600/309 |
| * | E | US-6,711,423 B2 | 03-2004 | Colvin, Jr., Arthur E. | 600/317 |
| * | G | US-6,800,060 B2 | 10-2004 | Marshall, Daniel R. | 600/309 |
| * | H | US-7,083,578 B2 | 08-2006 | Lewkowicz et al. | 600/593 |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
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| | Q | | | | | |
| | R | | | | | |
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| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

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